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PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Khazeni et al. Atty. Dckt. HDI 103
Serial No. 10/804,926 Examiner: Unknown
Filed: 03/19/2004 Grp Art Unit: 2877
For: Improved Reflectance
 Surface Analyzer

Certificate of Mailing

I, Stanley Z. Cole, hereby certify that this paper is being mailed first class mail with the U.S. Postal Service with proper postage affixed addressed to the Commissioner for Patents P.O Box 1450, Alexandria, VA 22313-1450 on the date set forth below.

Date: August 10, 2004

Signed

Statement Filed Pursuant To The Duty To Disclose Under 37 CFR § 1.56, §1.97 and §1.98

Honorable Commissioner of Patents and Trademarks:

Pursuant to the duty to disclose under 37 CFR §§1.56, 1.97 and 1.98, Applicants request consideration of this Information Disclosure Statement.

This Information Disclosure Statement is being filed prior to the first Office Action on the merits in the above-identified case. No fee or certificate is therefore required.

Applicants make of record in the above-identified application the prior art listed on the attached form PTO/SB/08A and 8B (2 pages).

A copy of each of the listed patents and the listed publication is attached.

In connection with the submitted art, it is all cited as background information relating to Surface Reflectance Analyzers.

References A, B, C and F have been cited as references directed to prior art Surface Reflectance Analyzers. All other cited references are cited as background technology to this invention.

It is respectfully requested that:

1. The Examiner consider completely the cited references in reaching a determination concerning the patentability of the claims in this application;
2. The Examiner sign the enclosed PTO form listing the references to evidence that the cited patents and publication have been fully considered by the Patent and Trademark Office during the examination of this application and that the references listed on the attached submission be printed on any patent that issues from this application.

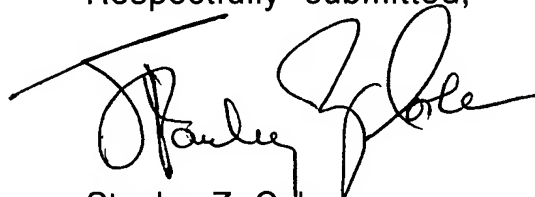
By submitting this Information Disclosure Statement, Applicants make no representation that a search has been made, or the extent of any search, or that more relevant information does not exist.

By submitting this Information Disclosure Statement, Applicants make no representation that the information cited in the Statement is,

or is considered to be, material to patentability as defined in 37 CFR §1.56 (b).

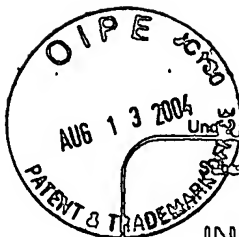
Notwithstanding any statement by Applicants the Examiner is urged to form his or her own conclusion(s) regarding the relevance of the cited references.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "Stanley Z. Cole", with a long horizontal stroke extending to the left.

Stanley Z. Cole
Registration No. 17,654
Applicants Attorney

(650) 941-0887
August 10, 2004



PTO/SB-08A (03-03)

Approved for use through 07/31/2008. OMB 0551-0031
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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Substitute for form 1449/PTO

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1

of 3

Complete if Known

Application Number	10/804,926
Filing Date	03/19/04
First Named Inventor	Khazeni, K.
Art Unit	2877
Examiner Name	Unknown
Attorney Docket Number	HDI-103

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	A	US- 6,515,745 B2	02/04/2003	Vurens et al.	See Statement
	B	US- 6,307,627 B1	10/23/2001	Vurens	See Statement
	C	US- 6,134,011	10/17/2000	Klien et al.	See Statement
	D	US- 5,835,220	11/10/1998	Kazama et al.	See Statement
	E	US- 5,790,259	08/04/1998	Mizuhata et al.	See Statement
	F	US- 5,726,455	03/10/1998	Vurens	See Statement
	G	US- 5,644,562	07/01/1997	De Groot	See Statement
	H	US- 5,438,415	08/01/1995	Kazama et al.	See Statement
	J	US- 5,335,066	08/02/1994	Yamada et al.	See Statement
	K	US- 5,311,285	05/10/1994	Oshige et al.	See Statement
	L	US- 5,282,217	01/25/1994	Yamazaki	See Statement
	M	US- 5,102,222	04/07/1992	Berger et al.	See Statement
	N	US- 4,908,508	03/13/1990	Dubbeldam	See Statement
	O	US- 4,893,932	01/16/1990	Knollenberg	See Statement
	P	US- 4,872,758	10/10/1989	Miyazaki et al.	See Statement
	Q	US- 4,681,450	07/21/1987	Azzam	See Statement
	R	US- 4,585,348	04/29/1986	Chastang et al.	See Statement
	S	US- 5,517,312	05/14/1996	Finarov	See Statement
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ⁴ Number ⁴ Kind Code ⁵ (if known)				

Examiner
SignatureDate
Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with USPEP 608. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kind Code of USPTO Patent Documents at www.uspto.gov or MPEP 601.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant to place a check mark here if English language translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Correspondence for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Complete if Known	
		Application Number	10/804,926
		Filing Date	03/19/04
		First Named Inventor	Khazeni, K.
		Art Unit	2877
		Examiner Name	Unknown
Sheet 2	of 2	Attorney Docket Number	HDI-103

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	T	AZZAM R.M.A. "Ellipsometry" Handbook of Optics: Devices, Measurements & Properties Vol II, 2nd Edition, Bass, M. et al.(eds).	
		McGraw Hill, Inc.: Chapter 27, pp. 27-1 - 27.26 (1995)	
	U	MEEKS, S. et al. "Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks" Transactions of the ASME, presented Oct 1994, Maui, HI	
	V	BRIGHT, D. et al. "Concentration histogram imaging: a quantitative view of related images" Microscopy: The Key Research Toll, March 1992 pp. 21-28	
	W	KLEIN, D. et al. "Measurements of Thin Film Disks by Surface Reflectance Analysis" SPIE Conference on Surface Characterization for Computer Disks,	
		Wafers and Flat Panel Displays, San Jose, CA January 1999, Volume 3619, pp. 18 - 26	
	X	Optics, MILES V. KLEIN and THOMAS E. FURTAK, Second Edition, Wiley, pp. 134 - 135	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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